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| Notice of References Cited | Application/Control No. 10/589,030 | Applicant(s)/Patent Under Reexamination SCHALK ET AL. | |
| | Examiner Andrés López-Esquerro | Art Unit 2818 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-2002/0190661 | 12-2002 | Duggal et al. | 315/169.1 |
| * | B | US-4,769,292 | 09-1988 | Tang et al. | 428/690 |
| * | C | US-4,933,053 | 06-1990 | Tieke, Bernd | 205/419 |
| * | D | US-2003/0219924 | 11-2003 | Bez et al. | 438/102 |
| * | E | US-5,869,843 | 02-1999 | Harshfield, Steven T. | 257/5 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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